



Low Power Quad Channels Digital Isolators

Check for Samples: ISO7640FM, ISO7641FM

FEATURES

- Signaling Rate: 150 Mbps
- Low Power Consumption, Typical I_{CC} per Channel (3.3 V Supplies):
 - ISO7640FM: 2 mA at 25 Mbps
 - ISO7641FM: 2.4 mA at 25 Mbps
- · Low Propagation Delay: 7 ns Typical
- · Output Defaults to Low-state in fail-safe mode
- Wide Temperature Range: -40°C to 125°C
- 50 KV/µs Transient Immunity, Typical
- Long Life with SiO₂ Isolation barrier
- Operates From 2.7V, 3.3 V and 5 V Supply and Logic Levels
- Wide Body SOIC-16 Package

APPLICATIONS

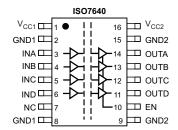
- Optocoupler Replacement in:
 - Industrial Fieldbus
 - Profibus
 - Modbus
 - DeviceNetTM Data Buses
 - Servo Control Interface
 - Motor Control
 - Power Supplies
 - Battery Packs

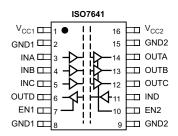
SAFETY AND REGULATORY APPROVALS

- 6000 V_{PK} / 4243 V_{RMS} for 1 Minute per UL 1577 (approved)
- VDE Approval for DIN EN 60747-5-2 (VDE 0884 Rev. 2), 1414 V_{PK} Working Voltage (approved)
- CSA Component Acceptance Notice 5A, IEC 60601-1 Medical Standard (approved)
- 5 KV_{RMS} Reinforced Insulation per TUV for EN/UL/CSA 60950-1 and EN/UL/CSA 61010-1 (approved)

DESCRIPTION

ISO7640FM and ISO7641FM provide galvanic isolation up to 6 KV $_{PK}$ for 1 minute per UL and VDE. These devices are also certified up to 5 KV $_{RMS}$ Reinforced isolation at a working voltage of 400 V $_{RMS}$ per end equipment standards EN/UL/CSA 60950-1 and 61010-1. ISO7640F and ISO7641F are quad channel isolators; ISO7640F has four forward and ISO7641F has three forward and one reverse direction channels. Suffix F indicates that output defaults to Low-state in fail-safe conditions (see Table 1). M-Grade devices are high speed isolators capable of 150 Mbps data rate with fast propagation delays







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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION CONTINUED

Each isolation channel has a logic input and output buffer separated by a silicon dioxide (SiO_2) insulation barrier. Used in conjunction with isolated power supplies, these devices prevent noise currents on a data bus or other circuits from entering the local ground and interfering with or damaging sensitive circuitry. The devices have TTL input thresholds and can operate from 2.7 V, 3.3 V and 5 V supplies. All inputs are 5 V tolerant when supplied from 3.3 V or 2.7 V supplies.

PIN DESCRIPTIONS

	PIN	PIN		DESCRIPTION
NAME	ISO7640	ISO7641	I/O	DESCRIPTION
INA	3	3	I	Input, channel A
INB	4	4	I	Input, channel B
INC	5	5	I	Input, channel C
IND	6	11	I	Input, channel D
OUTA	14	14	0	Output, channel A
OUTB	13	13	0	Output, channel B
OUTC	12	12	0	Output, channel C
OUTD	11	6	0	Output, channel D
EN	10	-	I	Enables (when input is High or Open) or Disables (when input is Low) OUTA, OUTB, OUTC and OUTD of ISO7640
EN1	-	7	I	Enables (when input is High or Open) or Disables (when input is Low) OUTD of ISO7641
EN2	-	10	I	Enables (when input is High or Open) or Disables (when input is Low) OUTA, OUTB, and OUTC of ISO7641
V _{CC1}	1	1	-	Power supply, V _{CC1}
V _{CC2}	16	16	_	Power supply, V _{CC2}
GND1	2,8	2,8	-	Ground connection for V _{CC1}
GND2	9,15	9,15	-	Ground connection for V _{CC2}
NC	7	-	-	No Connect pins are floating with no internal connection

Table 1. FUNCTION TABLE(1)

INPUT V _{CC}	OUTPUT V _{CC}	INPUT (INx)	OUTPUT ENABLE (ENx)	OUTPUT (OUTx)
		H H or Open		Н
DII	PU	L	H or Open	L
PU		X	L	Z
		Open	H or Open	L
PD	PU	Х	H or Open	L
PD	PU	Х	L	Z
PU	PD	Х	X	Undetermined

(1) PU = Powered Up($V_{CC} \ge 2.7 \text{ V}$); PD = Powered Down ($V_{CC} \le 2.1 \text{ V}$); X = Irrelevant; H = High Level; L = Low Level; Z = High Impedance



AVAILABLE OPTIONS

PRODUCT	RATED ISOLATION	PACKAGE	INPUT THRESHOLD	DATA RATE and FILTER	CHANNEL DIRECTION	MARKED AS	ORDERING NUMBER
ISO7640FM	6 KV _{PK} / 5 KV _{RMS} ⁽¹⁾		1.5 V TTL (CMOS Compatible)		4 Forward,	ISO7640FM	ISO7640FMDW (rail)
13070401 W		DW-16		150 Mbps, No Noise Filter	0 Reverse	13070401 W	ISO7640FMDWR (reel)
ISO7641FM		סו-יייט			3 Forward,	ISO7641FM	ISO7641FMDW (rail)
1307041FW					1 Reverse	130/041FW	ISO7641FMDWR (reel)

⁽¹⁾ See the Regulatory Information table for detailed isolation ratings.

ABSOLUTE MAXIMUM RATINGS(1)

DADAMETED				VA	LUE	LINUT
PARAMETER				MIN	-0.5 6 -0.5 6 ±15 ±4 ±1.5 ±200 150	UNIT
Supply voltage ⁽²⁾	V _{CC1} , V _{CC2}				6	V
Voltage	INx, OUTx, ENx			-0.5	6	٧
Output Current, I _O	Dutput Current, I _O				±15	mA
	Human Body Model	Body Model ESDA, JEDEC JS-001-2012			±4	kV
Electrostatic discharge	Field-Induced Charged Device Model	JEDEC JESD22-C101E	All pins	#4 All pins ±1.5 ±200	±1.5	kV
	Machine Model	JEDEC JESD22-A115-A			V	
Maximum junction temperature, T _J					150	°C
Storage temperature, T _{STO}	3			-65	150	°C

⁽¹⁾ Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating*Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

PARAMETER			MIN	TYP	MAX	UNIT
Supply voltage	V _{CC1} , V _{CC2}		2.7		5.5	V
High-level output current	I _{OH}		-4			mA
Low-level output current	I _{OL}				4	mA
High-level input voltage	V_{IH}		2		V_{CC}	V
Low-level input voltage	V _{IL}		0		0.8	V
lanut nules dunation		≥3V-Operation	6.67			
input puise duration	τ _{ui}	<3V-Operation	10			ns
Cinnalian sata	4 / 4	≥3V-Operation	0		5.5 4 V _{CC}	Mana
Input pulse duration t _{ui} <3V-Operation 10	100	Mbps				
Junction temperature	TJ		-40		136	°C
Ambient temperature	T _A		-40	25	125	°C

Product Folder Links: ISO7640FM ISO7641FM

Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values except differential I/O bus voltages are with respect to the local ground terminal (GND1 or GND2) and are peak voltage values.

TEXAS INSTRUMENTS

THERMAL INFORMATION

	TUEDMA	AL METRIC ⁽¹⁾	ISO76xx	UNITS
	ITERWIA	AL METRIC (DW (16 Pins)	UNITS
θ_{JA}	Junction-to-ambient thermal resistance	ce	72	
$\theta_{JC(top)}$	Junction-to-case(top) thermal resistar	nction-to-case(top) thermal resistance		
θ_{JB}	Junction-to-board thermal resistance	39	90044	
ΨЈТ	Junction-to-top characterization parar	meter	9.4	°C/W
ΨЈВ	Junction-to-board characterization pa	rameter	n/a	
θ _{JC(bottom)}	Junction-to-case(bottom) thermal resi	istance	n/a	
P _D	Maximum Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.5V$, $T_J = 150^{\circ}C$, $C_L = 15pF$ Input a 75 MHz 50% duty cycle square wave	399	mW

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

ELECTRICAL CHARACTERISTICS

 V_{CC1} and V_{CC2} at 5 V \pm 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	High lavel output valtage	I _{OH} = -4 mA; see Figure 1	V _{CCx} ⁽¹⁾ - 0.8	4.8		V
V _{OH}	High-level output voltage	I _{OH} = -20 μA; see Figure 1	$V_{CCx}^{(1)} - 0.1$	5		V
	Low lovel output voltage	I _{OL} = 4 mA; see Figure 1		0.2	0.4	V
V _{OL}	Low-level output voltage	I _{OL} = 20 μA; see Figure 1		0	0.1	
V _{I(HYS)}	Input threshold voltage hysteresis			450		mV
I _{IH}	High-level input current	V _{IH} = V _{CC} at INx or ENx			10	
I _{IL}	Low-level input current	V _{IL} = 0 V at INx or ENx	-10			μA
CMTI	Common-mode transient immunity	V _I = V _{CC} or 0 V; see Figure 4	25	75		kV/μs

⁽¹⁾ V_{CCx} is the supply voltage, V_{CC1} or V_{CC2} , for the output channel that is being measured.

SWITCHING CHARACTERISTICS

 V_{CC1} and V_{CC2} at 5 V \pm 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t _{PLH} , t _{PHL}	Propagation delay time	See Figure 1	3.5	7	10.5		
PWD ⁽¹⁾	Pulse width distortion t _{PHL} - t _{PLH}	See Figure 1			2		
4 (2)	Channel to abannel autout akeyy time	Same-direction Channels			2	ns	
t _{sk(o)} (2)	Channel-to-channel output skew time	Opposite-direction Channels			3		
t _{sk(pp)} (3)	Part-to-part skew time				4.5		
t _r	Output signal rise time	Con Figure 4		1.6			
t _f	Output signal fall time	See Figure 1		1		ns	
t _{PHZ}	Disable Propagation Delay, high-to-high impedance output			5	16		
t _{PLZ}	Disable Propagation Delay, low-to-high impedance output	See Figure 2		5	16	no	
t _{PZH}	Enable Propagation Delay, high impedance-to- high output	See rigule 2		4	16	ns	
t _{PZL}	Enable Propagation Delay, high impedance-to-low output			4	16		
t _{fs}	Fail-safe output delay time from input data or power loss	See Figure 3		9.5		μs	

⁽¹⁾ Also known as Pulse Skew.

⁽z) t_{sk(o)} is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.

⁽³⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.



SUPPLY CURRENT

 V_{CC1} and V_{CC2} at 5 V \pm 10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ISO7640FM						
I _{CC1}	Disable	EN = 0 V		0.6	1.2	
I _{CC2}	Disable			4.5	6.6	
I _{CC1}	DC to 1 Mbps			0.7	1.3	ı
I _{CC2}	DC to 1 Mbps			4.6	6.7	
I _{CC1}	10 Mbps			1.1	2	mA
I _{CC2}	TO MIDPS	DC Signal: $V_I = V_{CC}$ or 0 V, AC Signal: All channels switching with square wave clock		6.6	10.5	ША
I _{CC1}	25 Mbps input; C _L = 15 pF		1.9	3		
I _{CC2}	25 IVIDPS			9.7	14.7	
I _{CC1}	150 Mbps			8.2	14.5	
I _{CC2}				35	58	
ISO7641FM	,					
I _{CC1}	Disable	EN1 = EN2 = 0 V		2.6	4.2	
I _{CC2}	Disable	EINI = EINZ = U V		4.2	6.8	
I _{CC1}	DC to 1 Mbps			2.7	4.3	
I _{CC2}	DC to 1 Mbps			4.3	6.9	
I _{CC1}	10 Mbps			3.6	4.9	mA
I _{CC2}	TO Mibbs	DC Signal: $V_1 = V_{CC}$ or 0 V,		6	8.2	ША
I _{CC1}	25 Mbps	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		5.1	6.6	
I _{CC2}	25 Mbps			8.8	11.4	
I _{CC1}	150 Mbps			17	22	
I _{CC2}	150 Mbps			31	42	



ELECTRICAL CHARACTERISTICS

 V_{CC1} at 5 V \pm 10% and V_{CC2} at 3.3 V \pm 10% (over recommended operating conditions unless otherwise noted)

001	002	,		I			
	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		$I_{OH} = -4$ mA; see	OUTx on V _{CC1} (5V) side	V _{CC1} - 0.8	4.8		
.,	High lavel autout valtage	Figure 1	OUTx on V _{CC2} (3.3V) side	V _{CC2} - 0.4	3		.,
V _{OH}	High-level output voltage	$I_{OH} = -20 \mu A$; see	OUTx on V _{CC1} (5V) side	V _{CC1} - 0.1	5		V
		Figure 1	OUTx on V _{CC2} (3.3V) side	V _{CC2} - 0.1	3.3		
V Low level output veltage	Laurianal antoni malta aa	I _{OL} = 4 mA; see Figure 1			0.2	0.4	
VOL	OL Low-level output voltage	I _{OL} = 20 μA; see Figu	ure 1		0	0.1	V
V _{I(HYS)}	Input threshold voltage hysteresis				430		mV
I _{IH}	High-level input current	V _{IH} = V _{CC} at INx or E	Nx			10	
I _{IL}	Low-level input current	V _{IL} = 0 V at INx or El	V _{IL} = 0 V at INx or ENx				μΑ
CMTI	Common-mode transient immunity	V _I = V _{CC} or 0 V; see	Figure 4	25	50		kV/μs

SWITCHING CHARACTERISTICS

 V_{CC1} at 5 V ± 10% and V_{CC2} at 3.3 V ± 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
t _{PLH} , t _{PHL}	Propagation delay time	Con Figure 4	4	8	13		
PWD ⁽¹⁾	Pulse width distortion t _{PHL} - t _{PLH}	See Figure 1			2		
4 (2)	Channel to channel output along time	Same-direction Channels			2.5	ns	
t _{sk(0)} (2)	Channel-to-channel output skew time	Opposite-direction Channels			3.5		
t _{sk(pp)} (3)	Part-to-part skew time				6		
t _r	Output signal rise time	Con Figure 4		2	ns		
t _f	Output signal fall time	See Figure 1		1.2		115	
t _{PHZ}	Disable Propagation Delay, high-to-high impedance output			6.5	17		
t _{PLZ}	Disable Propagation Delay, low-to-high impedance output	Coo Figure 2		6.5	17		
t _{PZH}	Enable Propagation Delay, high impedance-to- high output	See Figure 2		5.5	17	ns	
t _{PZL}	Enable Propagation Delay, high impedance-to-low output			5.5	17		
t _{fs}	Fail-safe output delay time from input data or power loss	See Figure 3		9.5		μs	

⁽¹⁾ Also known as Pulse Skew.

⁽²⁾ t_{sk(0)} is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.

⁽³⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.



SUPPLY CURRENT

 V_{CC1} at 5 V \pm 10% and V_{CC2} at 3.3V \pm 10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ISO7640FM						
I _{CC1}	Disable	EN = 0 V		0.6	1.2	
I _{CC2}	Disable	EIN = 0 V		3.6	5.1	
I _{CC1}	DC to 1 Mbps			0.7	1.3	
I _{CC2}	DC to 1 Mbps			3.7	5.2	
I _{CC1}	10 Mbps	DC Signal: V _I = V _{CC} or 0 V,		1.1	2	mA
I _{CC2}	TO MIDPS			5	7.1	IIIA
I _{CC1}	OF Mhno	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		1.9	3	
I _{CC2}	25 Mbps			6.9	11	
I _{CC1}	150 Mbps			8.2	14.5	
I _{CC2}				24	40	
ISO7641FM						
I _{CC1}	514 510 04		2.6	4.2		
I _{CC2}	Disable	EN1 = EN2 = 0 V		3.2	4.9	
I _{CC1}	DO to 4 Mb			2.7	4.3	
I _{CC2}	DC to 1 Mbps			3.3	5	
I _{CC1}	40 Mb			3.6	4.9	A
I _{CC2}	10 Mbps	DC Signal: V _I = V _{CC} or 0 V,		4.4	5.8	mA
I _{CC1}	05 Mb	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		5.1	6.6	
I _{CC2}	25 Mbps			6.1	7.6	
I _{CC1}	450 141			17	22	
I _{CC2}	150 Mbps			20.6	26.5	



ELECTRICAL CHARACTERISTICS

 V_{CC1} at 3.3 V ± 10% and V_{CC2} at 5 V ± 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
		I _{OH} = -4 mA; see Figure 1	OUTx on V _{CC1} (3.3 V) side	V _{CC1} -0.4	3		
V High lovel output	High lavel autout valtage		OUTx on V _{CC2} (5 V) side	V _{CC2} -0.8	4.8		V
V _{OH}	High-level output voltage	$I_{OH} = -20 \mu A$; see Figure 1	OUTx on V _{CC1} (3.3 V) side	V _{CC1} -0.1	3.3		V
			OUTx on V _{CC2} (5 V) side	V _{CC2} -0.1	5		
V	Low lovel output voltage	I _{OL} = 4 mA; see Figure 1			0.2	0.4	V
V _{OL}	Low-level output voltage	I_{OL} = 20 μ A; see Figure 1			0	0.1	V
V _{I(HYS)}	Input threshold voltage hysteresis				430		mV
I _{IH}	High-level input current $V_{IH} = V_{CC}$ at INx or ENx				10		
I _{IL}	Low-level input current	V _{IL} = 0 V at INx or ENx		-10			μA
CMTI	Common-mode transient immunity	V _I = V _{CC} or 0 V; see Figure 4	·	25	50		kV/μs

SWITCHING CHARACTERISTICS

 V_{CC1} at 3.3 V ± 10% and V_{CC2} at 5 V ± 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay time	Con Figure 4	4	7.5	12.5	
PWD ⁽¹⁾	Pulse width distortion t _{PHL} - t _{PLH}	See Figure 1			2	
4 (2)	Channel to channel output along time	Same-direction Channels			2.5	ns
$t_{sk(0)}^{(2)}$	Channel-to-channel output skew time	Opposite-direction Channels			3.5	
t _{sk(pp)} (3)	Part-to-part skew time				6	
t _r	Output signal rise time	Con Figure 4		1.7		
t _f	Output signal fall time	See Figure 1		1.1		ns
t _{PHZ}	Disable Propagation Delay, high-to-high impedance output			5.5	17	
t _{PLZ}	Disable Propagation Delay, low-to-high impedance output	See Figure 2		5.5	17	20
t _{PZH}	Enable Propagation Delay, high impedance-to-high output	See Figure 2		4.5	17	ns
t _{PZL}	Enable Propagation Delay, high impedance-to-low output			4.5	17	
t _{fs}	Fail-safe output delay time from input data or power loss	See Figure 3		9.5		μs

⁽¹⁾ Also known as Pulse Skew.

⁽²⁾ t_{sk(0)} is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.

⁽³⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.



SUPPLY CURRENT

 V_{CC1} at 3.3 V \pm 10% and V_{CC2} at 5 V \pm 10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ISO7640FM	-1					
I _{CC1}	Disable	EN = 0 V		0.35	0.7	
I _{CC2}	Disable	EN = 0 V		4.5	6.6	
I _{CC1}	DC to 1 Mbps			0.4	0.8	
I _{CC2}	DC to 1 Mbps			4.6	6.7	
I _{CC1}	10 Mbps			0.7	1.2	mA
I _{CC2}	- TO MIDPS	DC Signal: V _I = V _{CC} or 0 V,		6.6	10.5	mA
I _{CC1}	25 Mbps	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		1.1	2	
I _{CC2}	25 IVIDPS			9.7	14.7	
I _{CC1}	150 Mbps			5	8.5	
I _{CC2}	150 Mbps	wipo		35	58	
ISO7641FM						
I _{CC1}	Disable	EN1 = EN2 = 0 V		1.9	2.9	
I _{CC2}	Disable	ENT = ENZ = 0 V		4.2	6.8	
I _{CC1}	DC to 1 Mbps			2	3	
I _{CC2}	DC to 1 Mbps			4.3	6.9	
I _{CC1}	10 Mbps			2.5	3.5	mA
I _{CC2}	10 Minh2	DC Signal: V _I = V _{CC} or 0 V,		6	8.2	IIIA
I _{CC1}	25 Mbps	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		3.4	4.5	
I _{CC2}				8.8	11.4	
I _{CC1}	150 Mbps			10.5	14.5	
I _{CC2}	150 Mbps			31	42	



ELECTRICAL CHARACTERISTICS

 V_{CC1} and V_{CC2} at 3.3 V \pm 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
.,	I link lavel a day do sale an	I _{OH} = -4 mA; see Figure 1	V _{CCx} ⁽¹⁾ - 0.4	3		V
V _{OH}	High-level output voltage	$I_{OH} = -20 \mu A$; see Figure 1	V _{CCx} ⁽¹⁾ – 0.1	3.3		V
V Low lovel output voltage	I _{OL} = 4 mA; see Figure 1		0.2	0.4	V	
VOL	V _{OL} Low-level output voltage	I_{OL} = 20 μ A; see Figure 1		0	0.1	V
V _{I(HYS)}	Input threshold voltage hysteresis			425		mV
I _{IH}	High-level input current	V _{IH} = V _{CC} at INx or ENx			10	
I _{IL}	Low-level input current	V _{IL} = 0 V at INx or ENx	-10			μA
CMTI	Common-mode transient immunity	V _I = V _{CC} or 0 V; see Figure 4	25	50		kV/µs

⁽¹⁾ V_{CCx} is the supply voltage, V_{CC1} or V_{CC2} , for the output channel that is being measured.

SWITCHING CHARACTERISTICS

 V_{CC1} and V_{CC2} at 3.3 V ± 10% (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay time	Oca Firmer 4	4	8.5	14	
PWD ⁽¹⁾	Pulse width distortion t _{PHL} - t _{PLH}	See Figure 1			2	
t _{sk(o)} (2)	Channel to abannel autnut alcourtime	Same-direction Channels			3	ns
l _{sk(o)} ` ′	Channel-to-channel output skew time	Opposite-direction Channels			4	
t _{sk(pp)} (3)	Part-to-part skew time				6.5	
t _r	Output signal rise time	Con Figure 4		2		
t _f	Output signal fall time	See Figure 1		1.3		ns
t _{PHZ}	Disable Propagation Delay, high-to-high impedance output			6.5	17	
t _{PLZ}	Disable Propagation Delay, low-to-high impedance output	Con Figure 0		6.5	17	
t _{PZH}	Enable Propagation Delay, high impedance-to-high output	See Figure 2		5.5	17	ns
t _{PZL}	Enable Propagation Delay, high impedance-to-low output			5.5	17	
t _{fs}	Fail-safe output delay time from input data or power loss	See Figure 3		9.2		μs

⁽¹⁾ Also known as Pulse Skew.

⁽²⁾ t_{sk(o)} is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.

⁽³⁾ $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.



SUPPLY CURRENT

 V_{CC1} and V_{CC2} at 3.3 V \pm 10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	ГҮР Г	MAX	UNIT
ISO7640FM						
I _{CC1}	Diaghla	Disable EN = 0 V	().35	0.7	
I _{CC2}	Disable	EN = U V		3.6	5.1	
I _{CC1}	DC to 1 Mbps			0.4	0.8	
I _{CC2}	DC to 1 Mbps			3.7	5.2	
I _{CC1}	10 Mbps			0.7	1.2	mA
I _{CC2}	10 Mbps	DC Signal: $V_1 = V_{CC}$ or 0 V, AC Signal: All channels switching with square wave clock input; $C_1 = V_{CC}$		5	7.1	IIIA
I _{CC1}	25 Mbps	15 pF		1.1	2	
I _{CC2}	25 Mbps		6.	6.9	11	
I _{CC1}	150 Mbps	50 Mbps		5	8.5	
I _{CC2}	150 Mbps			24	40	
ISO7641FM						
I _{CC1}	Disable EN1 = EN2 = 0 V	EN1 = EN2 = 0 V		1.9	2.9	
I _{CC2}	Disable	ENT = ENZ = 0 V		3.2	4.9	
I _{CC1}	DC to 1 Mbps			2	3	
I _{CC2}	DC to 1 Mbps			3.3	5	
I _{CC1}	10 Mbps			2.5	3.5	mA
I _{CC2}	10 Minh2	DC Signal: V _I = V _{CC} or 0 V,		4.4	5.8	IIIA
I _{CC1}	25 Mbps	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		3.4	4.5	
I _{CC2}	25 Mbps			6.1	7.6	
I _{CC1}	450 Mbns		,	0.5	14.5	
I _{CC2}	150 Mbps		2	20.6	26.5	



ELECTRICAL CHARACTERISTICS

 V_{CC1} and V_{CC2} at 2.7 $V^{(1)}$ (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{OH} Hi	I Bala Javas Lavatavatavas karas	I _{OH} = -4 mA; see Figure 1	V _{CC} ⁽²⁾ - 0.5	2.4		
	High-level output voltage $I_{OH} = -20 \mu A$; see Figure 1	I _{OH} = -20 μA; see Figure 1	V _{CC} ⁽²⁾ - 0.1	2.7		V
V _{OL}	Low lovel output voltege	I _{OL} = 4 mA; see Figure 1		0.2	0.4	
	Low-level output voltage	$I_{OL} = 20 \mu A$; see Figure 1		0	0.1	V
V _{I(HYS)}	Input threshold voltage hysteresis			350		mV
I _{IH}	High-level input current	$V_{IH} = V_{CC}$ at INx or ENx			10	
I _{IL}	Low-level input current	V _{IL} = 0 V at INx or ENx	-10			μA
CMTI	Common-mode transient immunity	V _I = V _{CC} or 0 V; see Figure 4	25	50		kV/μs

- (1) For 2.7 V-operation, max data rate is 100 Mbps.
- (2) V_{CCx} is the supply voltage, V_{CC1} or V_{CC2}, for the output channel that is being measured.

SWITCHING CHARACTERISTICS

V_{CC1} and V_{CC2} at 2.7 V (over recommended operating conditions unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay time	See Figure 4	5	8	16	
PWD ⁽¹⁾	Pulse width distortion t _{PHL} - t _{PLH}	See Figure 1			2.5	
4 (2)	Channel to shannel sutnut also utime	Same-direction Channels			4	ns
$t_{sk(o)}^{(2)}$	Channel-to-channel output skew time	Opposite-direction Channels			5	
$t_{sk(pp)}^{(3)}$	Part-to-part skew time				8	
t _r	Output signal rise time	See Figure 4		2.3		
t _f	Output signal fall time	See Figure 1		1.8		ns
t _{PHZ}	Disable Propagation Delay, high-to-high impedance output			8	18	
t _{PLZ}	Disable Propagation Delay, low-to-high impedance output	See Figure 2		8	18	
t _{PZH}	Enable Propagation Delay, high impedance-to- high output	See Figure 2		7	18	ns
t _{PZL}	Enable Propagation Delay, high impedance-to-low output			7	18	
t _{fs}	Fail-safe output delay time from input data or power loss	See Figure 3		8.5		μs

- (1) Also known as Pulse Skew.
- (z) t_{sk(o)} is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.
- (3) t_{sk(pp)} is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.



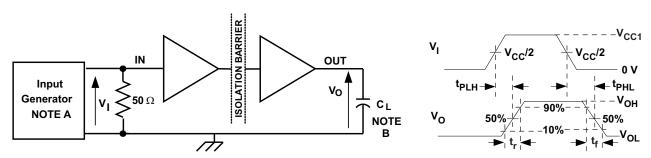
SUPPLY CURRENT

 V_{CC1} and V_{CC2} at 2.7 V (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ISO7640FM	-					
I _{CC1}	Disable	EN OV		0.2	0.6	
I _{CC2}	Disable	EN = 0 V		3.3	5	
I _{CC1}	DC to 1 Mbps			0.2	0.7	
I _{CC2}	DC to 1 Mbps			3.4	5.1	
I _{CC1}	10 Mbps			0.4	1.1	mA
I _{CC2}	25 Mbps	DC Signal: V _I = V _{CC} or 0 V,		4.4	6.8	MA
I _{CC1}		AC Signal: All channels switching with square wave clock input; C _L = 15 pF		0.8	1.8	
I _{CC2}				6	9.5	
I _{CC1}	100 Mbps			2.7	5	
I _{CC2}				14.2	21	
ISO7641FM		·				
I _{CC1}	Disable	EN1 = EN2 = 0 V		1.6	2.4	
I _{CC2}	Disable	EIN I = EINZ = U V		2.8	4.1	
I _{CC1}	DC to 1 Mbps			1.7	2.5	
I _{CC2}	DC to 1 Mbps			2.9	4.2	
I _{CC1}	10 Mbps			2.1	3	mA
I _{CC2}	TO Midps	DC Signal: V _I = V _{CC} or 0 V,		3.8	5	ША
I _{CC1}	25 Mbps	AC Signal: All channels switching with square wave clock input; C _L = 15 pF		2.8	3.8	
I _{CC2}				5.2	6.7	
I _{CC1}	100 Mbns			6.4	7.5	
I _{CC2}	100 Mbps			11.8	15.5	

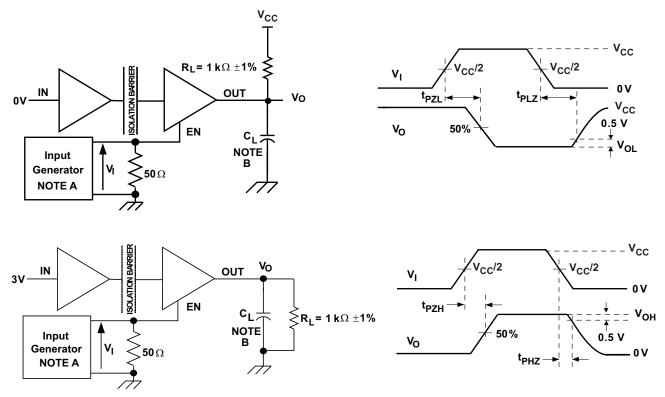


PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3ns, $Z_O =$ 50 Ω . At the input, 50 Ω resistor is required to terminate Input Generator signal. It is not needed in actual application.
- B. $C_1 = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 1. Switching Characteristics Test Circuit and Voltage Waveforms

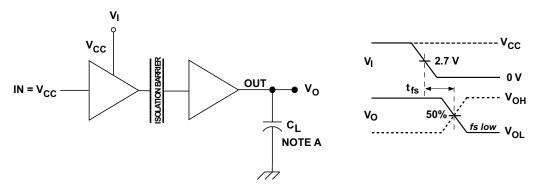


- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 10 kHz, 50% duty cycle, $t_f \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O =$ 50 Ω .
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform

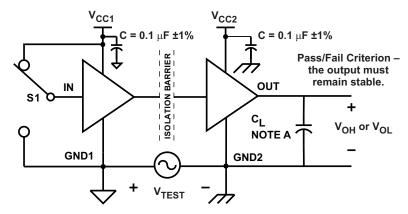


PARAMETER MEASUREMENT INFORMATION (continued)



A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 4. Common-Mode Transient Immunity Test Circuit



DEVICE INFORMATION

IEC INSULATION AND SAFETY-RELATED SPECIFICATIONS FOR DW-16 PACKAGE

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal to terminal distance through air	8.3			mm
L(I02) ⁽¹⁾	Minimum external tracking (Creepage)	Shortest terminal to terminal distance across the package surface	8.1			mm
СТІ	Tracking resistance (Comparative Tracking Index)	DIN IEC 60112 / VDE 0303 Part 1	≥400			V
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.014			mm
R _{IO} ⁽²⁾	Isolation resistance, Input to	V _{IO} = 500 V, T _A < 100°C		>10 ¹²		0
K _{IO} (-)	Output	V _{IO} = 500 V, 100°C ≤ T _A ≤ max		>10 ¹¹		Ω
C _{IO} ⁽²⁾	Barrier capacitance, Input to Output	$V_1 = 0.4 \sin (2\pi ft), f = 1MHz$		2		pF
C _I ⁽³⁾	Input capacitance	$V_1 = V_{CC}/2 + 0.4 \sin(2\pi ft), f = 1MHz, V_{CC} = 5 V$		2		pF

- (1) Per JEDEC package dimensions.
- (2) All pins on each side of the barrier tied together creating a two-terminal device.
- (3) Measured from input pin to ground.

NOTE

Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed circuit board do not reduce this distance.

Creepage and clearance on a printed circuit board become equal according to the measurement techniques shown in the Isolation Glossary. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.

DIN EN 60747-5-2 (VDE 0884 TEIL 2) INSULATION CHARACTERISTICS⁽⁴⁾

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	SPECIFICATION	UNIT
V_{IORM}	Maximum working insulation voltage (1)		1414	V _{PEAK}
		After Input/Output safety test subgroup 2/3, $V_{PR} = V_{IORM} \times 1.2$, $t = 10 \text{ s}$, Partial discharge < 5 pC	1697	
V_{PR}	Input-to-output test voltage	Method a, After environmental tests subgroup 1, $V_{PR} = V_{IORM} \times 1.6$, $t = 10 \text{ s}$, Partial Discharge < 5 pC	2262	V _{PEAK}
		Method b1, 100% Production test $V_{PR} = V_{IORM} \times 1.875$, $t = 1 \text{ s}$ Partial discharge < 5 pC	2652	
V_{IOTM}	Maximum transient overvoltage	V _{TEST} = V _{IOTM} t = 60 sec (Qualification) t = 1 sec (100% Production)	6000	V _{PEAK}
R _S	Insulation resistance	V _{IO} = 500 V at T _S	>10 ⁹	Ω
	Pollution degree		2	

(4) Climatic Classification 40/125/21

(1) For applications that require DC working voltages between GND1 and GND2, please contact Texas Instruments for further details.

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IEC 60664-1 RATINGS TABLE

PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic Isolation Group	Material Group	II
	Rated mains voltage ≤ 300 V _{RMS}	I–IV
Installation classification	Rated mains voltage ≤ 600 V _{RMS}	I–III
	Rated mains voltage ≤ 1000 V _{RMS}	I–II

REGULATORY INFORMATION

VDE	TUV	CSA	UL
Certified according to DIN EN 60747-5-2	Certified according to EN/UL/CSA 60950-1 and 61010- 1	Approved under CSA Component Acceptance Notice #5A	Recognized under 1577 Component Recognition Program
Basic Insulation Maximum Transient Overvoltage, 6000 V _{PK} Maximum Working Voltage, 1414 V _{PK}	5000 V _{RMS} Reinforced Insulation, 400 V _{RMS} maximum working voltage 5000 V _{RMS} Basic Insulation, 600 V _{RMS} maximum working voltage	5000 V _{RMS} Reinforced Insulation 2 Means of Patient Protection at 125 V _{RMS} per IEC 60601-1 (3rd Ed.)	Single Protection, 4243 V _{RMS} ⁽¹⁾
File Number: 40016131	Certificate Number: U8V 13 09 77311 010	File Number: 220991	File Number: E181974

⁽¹⁾ Production tested \geq 5092 V_{RMS} for 1 second in accordance with UL 1577.

IEC SAFETY LIMITING VALUES

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the IO can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
			$\theta_{JA} = 72 \text{ °C/W}, V_I = 5.5 \text{V}, T_J = 150 \text{ °C}, T_A = 25 \text{ °C}$			316	
Is	Safety input, output, or supply current	DW-16	$\theta_{JA} = 72 \text{ °C/W}, V_I = 3.6 \text{V}, T_J = 150 \text{ °C}, T_A = 25 \text{ °C}$			482	mA
	ourion		$\theta_{JA} = 72 \text{ °C/W}, V_I = 2.7V, T_J = 150 \text{ °C}, T_A = 25 \text{ °C}$			643	
T _S	Maximum case temperature					150	°C

The safety-limiting constraint is the absolute maximum junction temperature specified in the absolute maximum ratings table. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the *Thermal Information* table is that of a device installed on a High-K Test Board for Leaded Surface Mount Packages. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

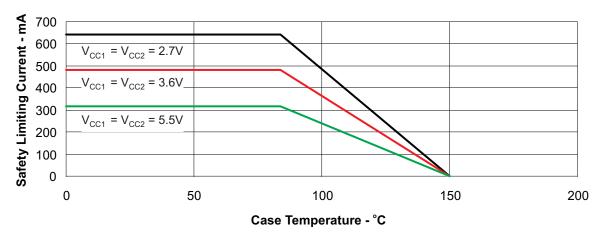
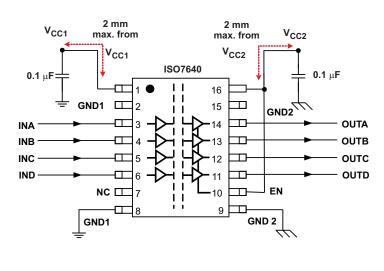


Figure 5. DW-16 θ_{JC} Thermal Derating Curve per IEC 60747-5-2

APPLICATION INFORMATION



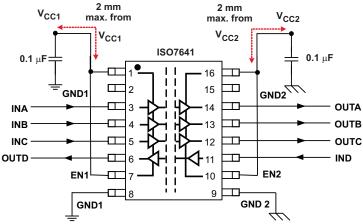


Figure 6. Typical ISO7640FM and ISO7641FM Application Circuit

Note: For detailed layout recommendations, see Application Note SLLA284, Digital Isolator Design Guide.



TYPICAL SUPPLY CURRENT EQUATIONS

(Calculated based on room temperature and typical Silicon process)

ISO7640FM:

At
$$V_{CC1} = V_{CC2} = 3.3V$$
 $I_{CC1} = 0.388 + 0.0312 \text{ x f}$
 $I_{CC2} = 3.39 + 0.03561 \text{ x f} + 0.006588 \text{ x f x C}_L$
At $V_{CC1} = V_{CC2} = 5V$
 $I_{CC1} = 0.584 + 0.05349 \text{ x f}$
 $I_{CC2} = 4.184 + 0.05597 \text{ x f} + 0.009771 \text{ x f x C}_L$

ISO7641FM:

At
$$V_{CC1} = V_{CC2} = 3.3V$$
 $I_{CC1} = 1.848 + 0.03233 \text{ x f} + 0.001645 \text{ x f x C}_L$
 $I_{CC2} = 3.005 + 0.03459 \text{ x f} + 0.0049395 \text{ x f x C}_L$
At $V_{CC1} = V_{CC2} = 5V$
 $I_{CC1} = 2.369 + 0.05385 \text{ x f} + 0.002448 \text{ x f x C}_L$
 $I_{CC2} = 3.857 + 0.05506 \text{ x f} + 0.007348 \text{ x f x C}_L$

 I_{CC1} and I_{CC2} are typical supply currents measured in mA; f is data rate measured in Mbps; C_L is the capacitive load on each channel measured in pF.

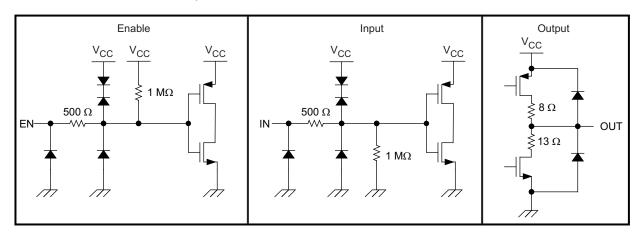


Figure 7. Device I/O Schematics



TYPICAL CHARACTERISTICS

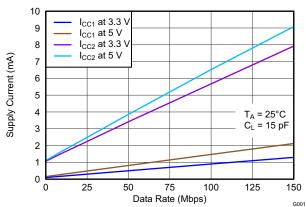


Figure 8. ISO7640FM Supply Current Per Channel vs Data Rate

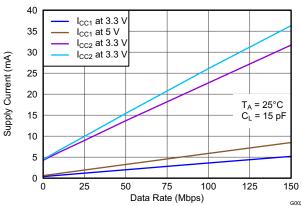


Figure 9. ISO7640FM Supply Current For All Channels vs Data Rate

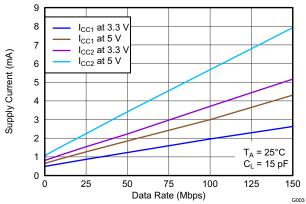
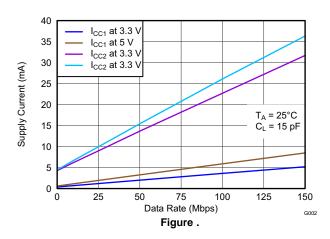
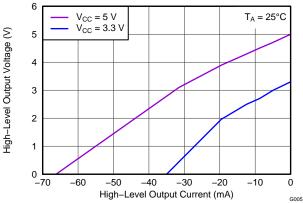


Figure 10. ISO7641FM Supply Current Per Channel vs Data Rate







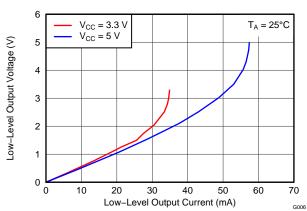
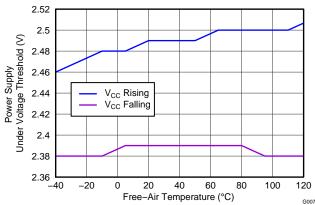


Figure 12. Low-Level Output Voltage vs Low-Level Output Current



TYPICAL CHARACTERISTICS (continued)



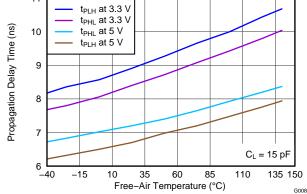


Figure 13. V_{CC} Undervoltage Threshold vs Free Air Temperature

Figure 14. Propagation Delay Time vs Free Air Temperature

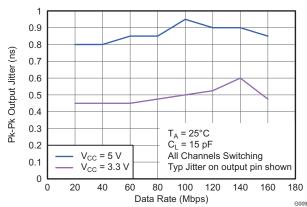
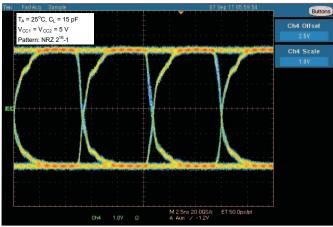


Figure 15. Output Jitter vs Data Rate



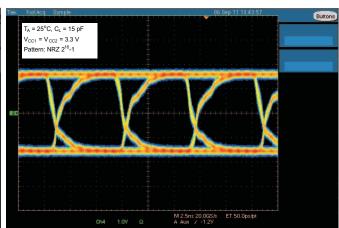


Figure 16. Typical Eye Diagram at 150 Mbps, 5 V Operation

Figure 17. Typical Eye Diagram at 150 Mbps, 3.3 V Operation



REVISION HISTORY

Cł	nanges from Original (September 2011) to Revision A	Page
•	Changed Figure 3 - From: 0 V or V _{CC} To: IN = V _{CC}	15
•	Added Note (1) "Per JEDEC package dimensions" to the IEC INSULATION AND SAFETY-RELATED	
	SPECIFICATIONS FOR DW-16 PACKAGE table	16
•	Changed L(I01) Min Value From: 8 mm To: 8.3 mm	16
•	Changed L(I02) Min Value From: 7.8 mm To: 8.1 mm	16
<u>•</u>	Added pinout for ISO7641 and ISO7631 to Figure 6	18
Cr	nanges from Revision A (October 2011) to Revision B	Page
•	Changed feature bullet From: ISO7641FC: 1.2 mA at 10 Mbps To: ISO7641FC: 1.3 mA at 10 Mbps	1
•	Changed Safety and Regulatory Approvals bullet From: 6 KV _{PK} for 1 Minute per UL1577 and VDE (Pending) To: 6000 V _{PK} / 4243 V _{RMS} for 1 Minute per UL 1577 (pending)	1
•	Changed Safety and Regulatory Approvals bullet From: To: 6000 V _{PK} / 4243 V _{RMS} for 1 Minute per UL 1577 (approved)	1
•	Changed Safety and Regulatory Approvals bullet From: CSA Component Acceptance Notice 5A, IEC 60601-1 Medical Standard (pending) To: CSA Component Acceptance Notice 5A, IEC 60601-1 Medical Standard (approved)	1
•	Changed all the ELECTRICAL CHARACTERISTICS tables	4
•	Changed all the SWITCHING CHARACTERISTICS tables	4
•	Changed the SWITCHING CHARACTERISTICS table ISO7640F and ISO7641F C-Grade values	<u>5</u>
•	Changed the SWITCHING CHARACTERISTICS table ISO7640F and ISO7641F C-Grade values	7
•	Changed the SWITCHING CHARACTERISTICS table ISO7640F and ISO7641F C-Grade values	9
•	Changed the SWITCHING CHARACTERISTICS table ISO7640F and ISO7641F C-Grade values	11
•	Changed the SWITCHING CHARACTERISTICS table ISO7640F and ISO7641F C-Grade values	13
•	Changed the IEC 60664-1 Ratings Table	17
Cr	nanges from Revision B (December 2011) to Revision C	Page
_	Changed Safety and Regulatory Approvals bullet From: 6000 V _{PK} / 4243 V _{RMS} for 1 Minute per UL1577 (pending)	
•	To: 6000 V_{PK} / 4243 V_{RMS} for 1 Minute per UL 1577 (approved)	1
•	Changed Description text From: The devices have TTL input thresholds and can operate from 2.7 V, 3.3 V and 5 V supplies. To: The devices have TTL input thresholds and can operate from 2.7 V (M-Grade), 3.3 V and 5 V supplies.	
•	Deleted the Product Preview Note From the Available Options Table	
•	Changed the ESD standards	
•	Changed UL in the REGULATORY INFORMATION Table From: File Number: E181974 (Approval Pending) To: File Number: E181974	
•	Changed the typical characteristics section	

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Cł	anges from Revision C (January 2012) to Revision D	Page
•	Deleted devices: ISO7631FM, ISO7631FC, ISO7640FC, ISO7641FC from the data sheet	1
•	Changed the Title From: Low Power Triple and Quad Channels Digital Isolators To: Low Power Quad Channels	
	Digital Isolators	1
•	Deleted devices from the Features List	1
•	Changed the DESCRIPTION	1
•	Changed EN1 and EN2 Pin Descriptions	2
•	Deleted device from the Available Options Table	3
•	Changed the ELECTRICAL, SWITCHING, and SUPPLY CURRENT CHARACTERISTICS tables	4
•	Changed the ELECTRICAL, SWITCHING, and SUPPLY CURRENT CHARACTERISTICS tables	6
•	Changed the ELECTRICAL, SWITCHING, and SUPPLY CURRENT CHARACTERISTICS tables	8
•	Changed the ELECTRICAL, SWITCHING, and SUPPLY CURRENT CHARACTERISTICS tables	10
•	Changed the ELECTRICAL, SWITCHING, and SUPPLY CURRENT CHARACTERISTICS tables	12
•	Deleted devices from the TYPICAL SUPPLY CURRENT EQUATIONS section	19
•	Changed the TYPICAL CHARACTERISTICS section	
Cł	nanges from Revision D (July 2012) to Revision E	Page
•	Changed Z to Undetermined in the OUTPUT (OUTx) column of the FUNCTION TABLE	2
Cł	nanges from Revision E (January 2013) to Revision F	Page
•	Changed the REGULATORY INFORMATION table, TUV column From: Certificate Number: U8V 13 07 77311 009 To: Certificate Number: U8V 13 09 77311 010	





26-Sep-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	_	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
ISO7640FMDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7640FM	Samples
ISO7640FMDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7640FM	Samples
ISO7641FMDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7641FM	Samples
ISO7641FMDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7641FM	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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PACKAGE OPTION ADDENDUM

26-Sep-2013

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	<u> </u>
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7640FMDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7641FMDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

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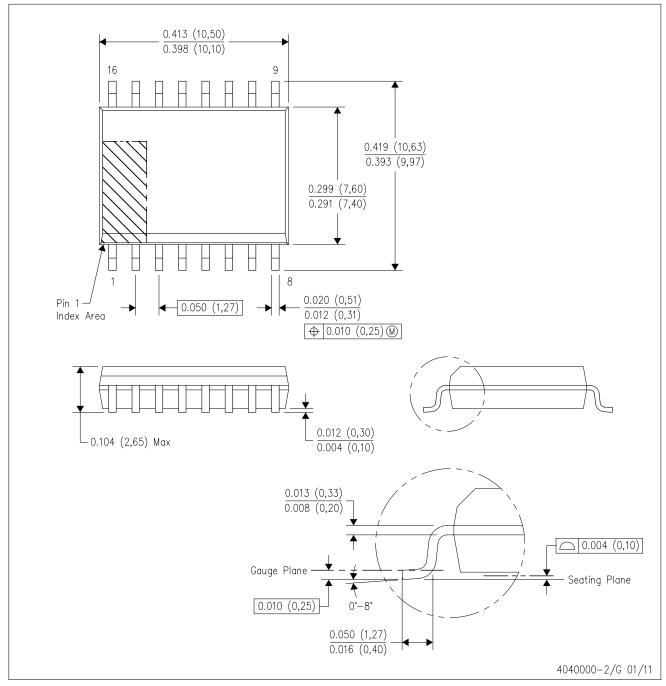


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7640FMDWR	SOIC	DW	16	2000	367.0	367.0	38.0
ISO7641FMDWR	SOIC	DW	16	2000	533.4	186.0	36.0

DW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



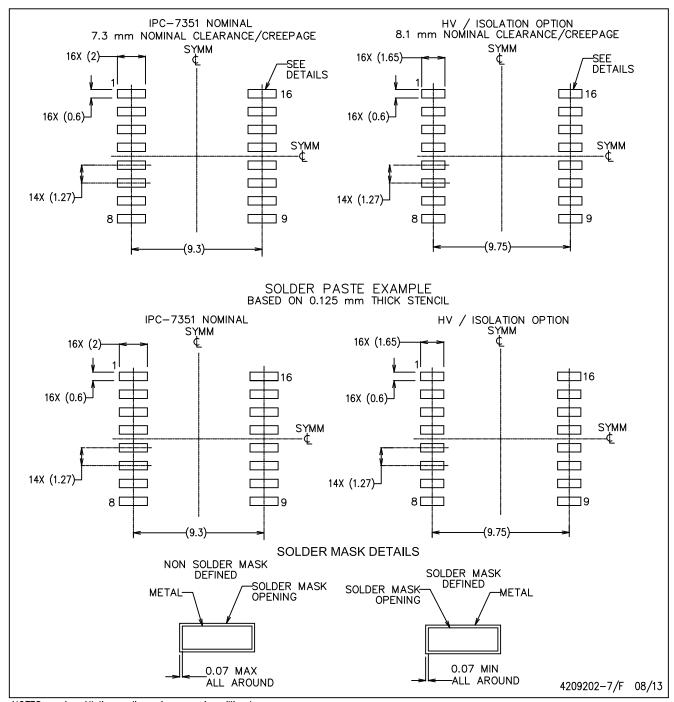
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AA.



DW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- E. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- F. Board assembly site may have different recommendations for stencil design.



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